

Search Notes				Application No.	Applicant(s)	
				10/083,877	WONG ET AL.	
				Examiner	Art Unit	
				David C. Meyer	2878	

SEARCHED			
Class	Subclass	Date	Examiner
250	237R	10/21 - 10/22	DCM
	341.8		
	306		
	307		
	559.3		
356	399		
	495		
	503		
	625		
	634		
	635		
	636		
	640	V	

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
Thanh Luu 250/ 237R, 559.3 text search scatterometry reflectometry ellipsometry	10/7/03	DCM
Richard Rosenberger 356/ 614, 616, 620 text search critical dimension scatterometry, ellipsometry, etc.	9/3/03	DCM

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

Search Notes (continued)	Application No.	Applicant(s)
	10/083,877	WONG ET AL.
	Examiner	Art Unit
	David C. Meyer	2878